

The Status and Future of Johnson Noise Thermometry

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Outline

Johnson noise thermometry

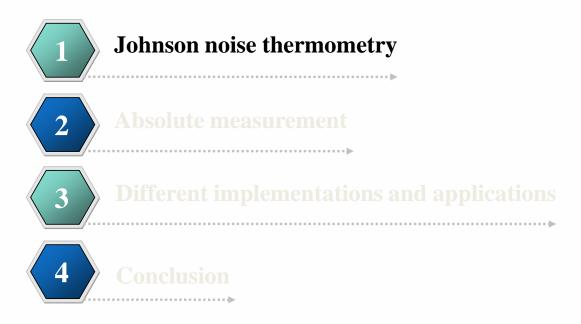
Absolute measurement

Different implementations and applications

Conclusion

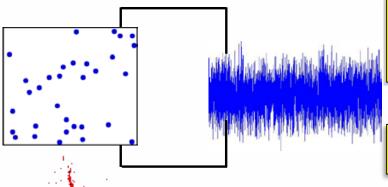


Outline





Johnson noise



$$S_R = 4hfR \frac{\acute{e}1}{\grave{e}2} + \frac{1}{\exp(hf/kT) - 1} \dot{\mathring{u}}$$
(1)

$$\langle V^2 \rangle = 4 \ kT R \ Df \tag{2}$$

- random thermal motion of electrons in a conductor causes both electrical resistance and a fluctuating voltage
- predicted by Einstein in 1906, measured by Johnson in 1927, and theoretically described by Nyquist in 1928
- fluctuation-dissipation theorem



Johnson noise thermometry



Pros:

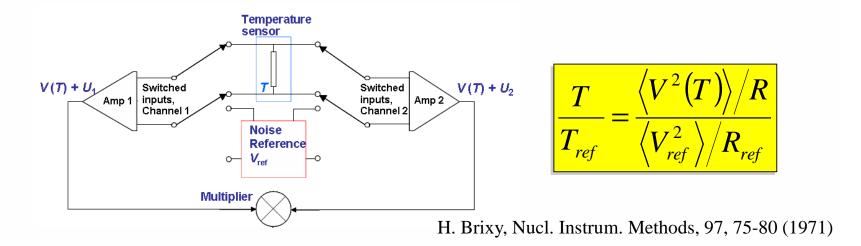
- pure electronic measurement of thermodynamic temperature
- immune from chemical and mechanical changes in the material properties
- periodic calibration is not necessary

Cons:

- extremely small voltage, 100 ohm, 273K, \sim 1.2nV/ $\sqrt{\rm Hz}$ (amplify by 10⁵)
- random, very long time integration ($\sigma \sim 1/\ddot{Q}$) (weeks or months)
- distributed over wide bandwidths $(\sigma \sim 1/\ddot{\Box} f)$ (a few hundred kHz)



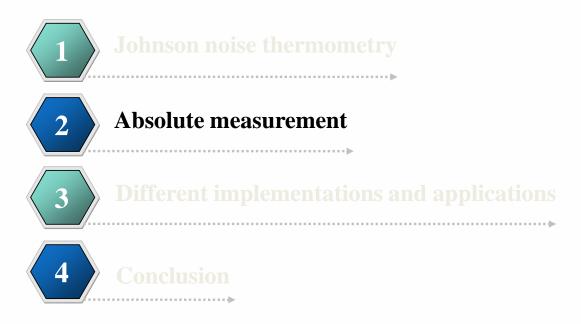
Switching correlator



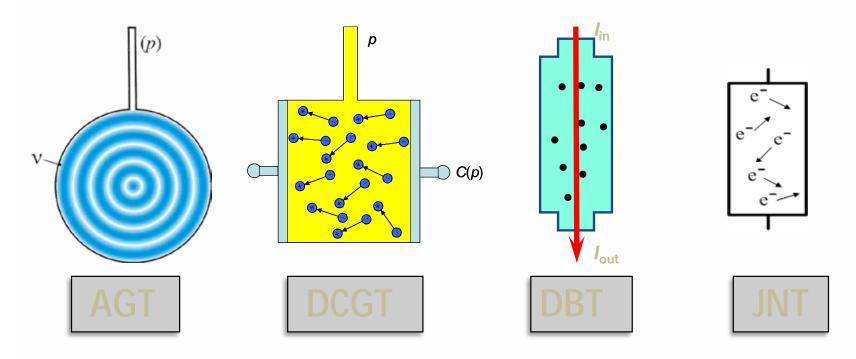
- four wire connection defines the source impedance
- **eliminates uncorrelated noise by cross-correlation**
- eliminates the effect of amplifier gain drift by switching
- impossible to match both the noise power and frequency response
- affected by electronic nonlinearity or narrow bandwidth
- relative measurement, uncertainty limited to 10⁻⁵



Outline



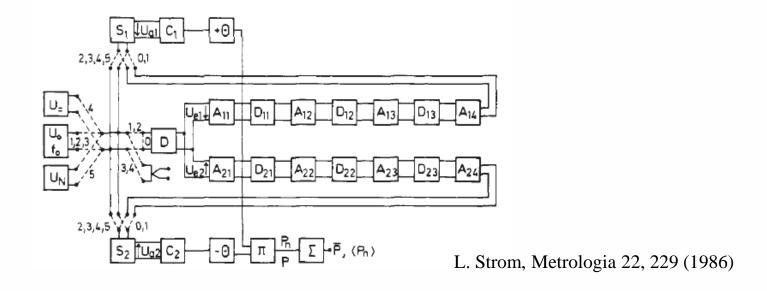




- **primary gas thermometry limited by non-ideal properties of real gas**
- **JNT uses electron gas**
- **pure electronic approach, attracting increasing interest**



Early attempt to measure $k_{\rm B}$

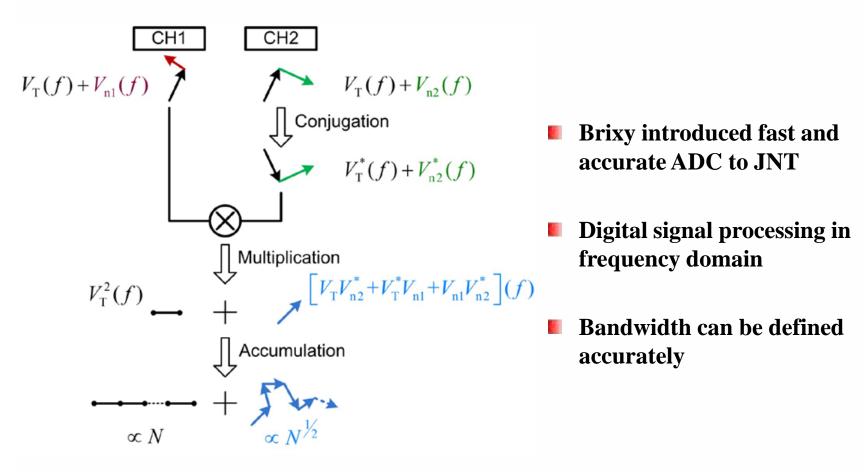


To achieve 10 ppm in $k_{\rm B}$ determination:

- 5 additional connections for calibration
- **keep the temperature of all electronics constant within 0.02 K**
- measure the divider factors with uncertainty less than 0.5 ppm
- **accumulate data for more than 1 year!**



Digital signal processing in frequency domain

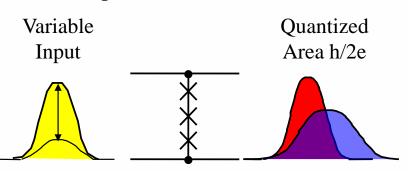


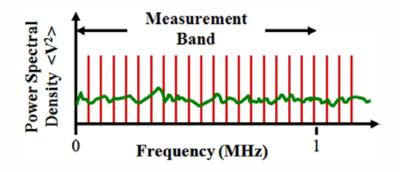
H. Brixy et. al., Temperature: It's measurement and control in science and industry, vol 6, 993 (1992)



Quantum voltage noise source

Josephson Pulse Quantizer





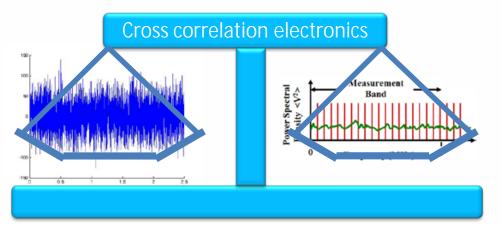
$$\mathbf{\dot{O}}(t)dt = \frac{h}{2e}$$

- Samuel Benz, Clark Hamilton (NIST)
- quantum accurate (<<1 ppm up to 4 MHz)</p>
- calculable PSD
- arbitrary distribution

S.P. Benz, and C. A. Hamilton Appl. Phys. Lett. 68, 3173 (1996)



Quantum voltage calibrated noise thermometer



Johnson noise

$$S_V$$



$$K_J^2 = \frac{4e^2}{h^2}$$

Quantum voltage noise

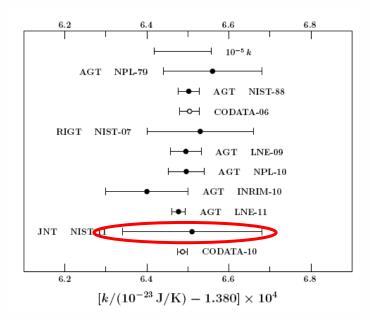
$$S_T \qquad R_K = \frac{h}{e^2}$$

$$k = \frac{\left\langle V_R^2 \right\rangle}{\left\langle V_Q^2 \right\rangle} \Big|_{f=0} \frac{\left\langle V_Q^2 \right\rangle_{cal}}{4TR}$$

John, Martinis (NIST)



Electronic measurement of $k_{\rm B}$

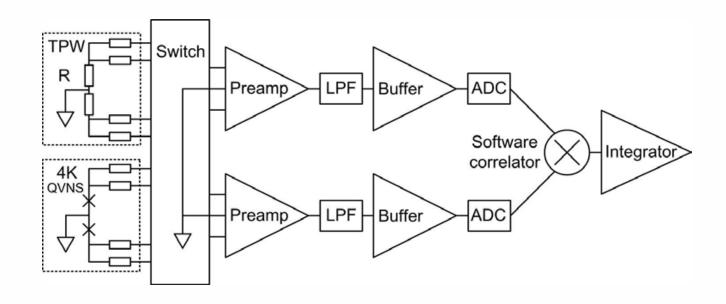


CODATA 2010 $k_{\rm B}$ input data

Mohr et al., *Rev. Mod. Phys.* 84 1527 (2012) Benz et al., *Metrologia* 48 142 (2011)

- NIST reported first electronic measurement of $k_{\rm B}$ with $u_{\rm r}=12.1$ 10^{-6}
- NIM/NIST collaboration, $u_r = 3.9 \cdot 10^{-6}$
- CCT required at least two methods with $u_r < 3' 10^{-6}$ to redefine the kelvin
- NIST, NIM, NMIJ, pursuing even lower uncertainty





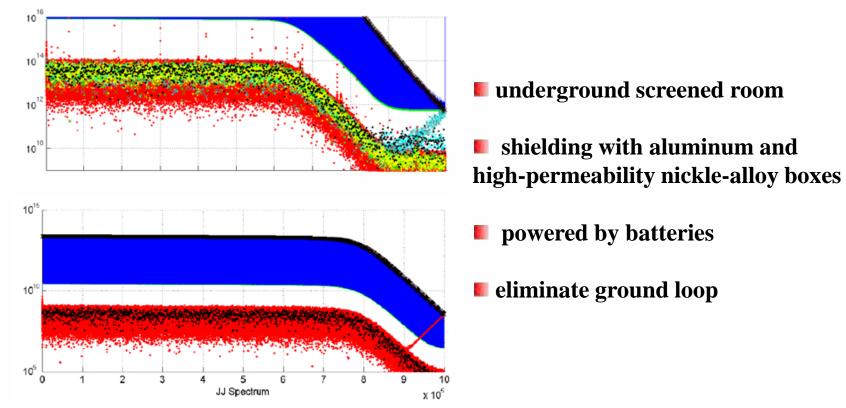
$$S_R = 4kT_{\rm W}X_RR_{\rm K}$$

$$S_{\text{Q-calc}} = D^2 N_{\text{J}}^2 f_{\text{s}} M / K_{\text{J}}^2$$

$$k = \frac{D^2 N_{\rm J}^2 f_{\rm s} M}{4T_{\rm W} X_{R} R_{\rm K} K_{\rm J}^2} \frac{\langle S_{R} \rangle}{\langle S_{\rm Q} \rangle}$$



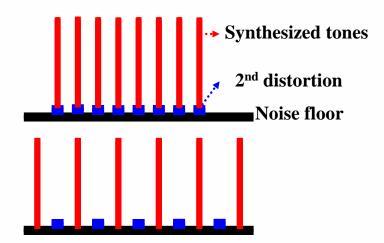
Shielding and grounding

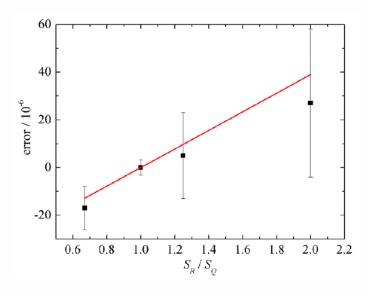


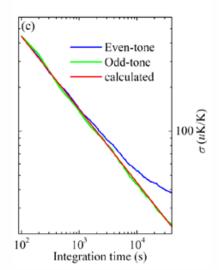
Measured spectra of the synthesized quantum noise waveform with (upper) and without (lower) observable EMI, blue green, and red are auto-correlation in each channel, and correlation spectra, respectively, and black ' is the synthesized tones.



Effect of nonlinearity



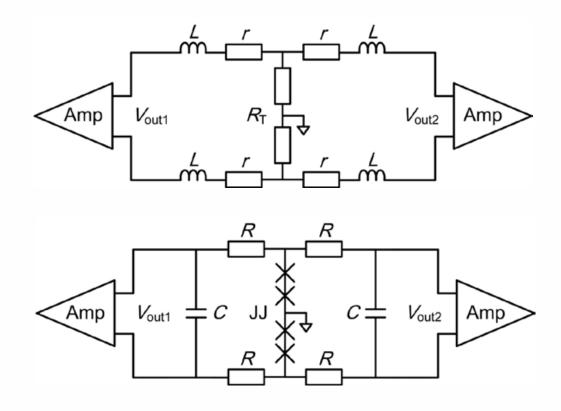




- **nonlinearity introduces significant errors**
- PSDs are the same, Gaussian distribution, uncorrelated noise power are the same
- change the voltage of QVNS without changing any other parameters to measure the nonlinearity effect
- ■~0. 4′ 10⁻⁶ error for 1% mismatch

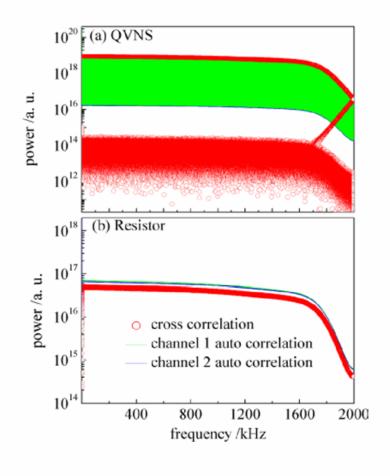


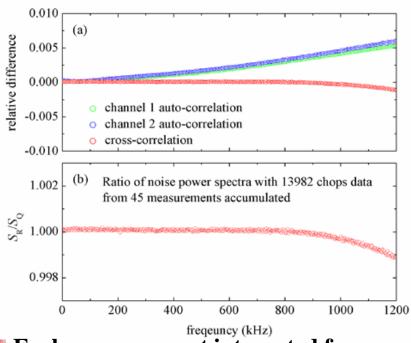
Match the noise sources and transmission lines



- **■** insert uncorrelated resistor to match both the noise powers and impedances
- **■** insert trimming inductance and capacitance to match the transmission lines

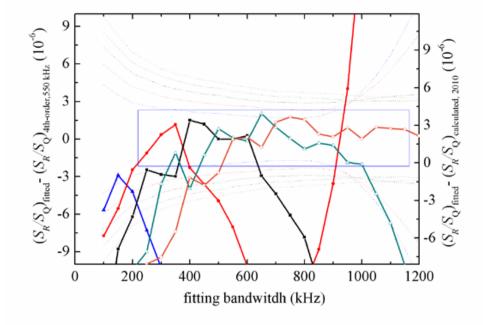






- Each measurement integrated for about 15-20 hours
- 45 measurements accumulated

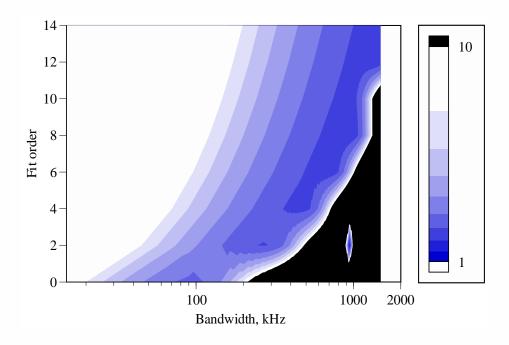




- short connections-lumped components
- even-order polynomial fit
- **■** increase bandwidth
- **uncertainty increase with the number of fitting parameters**
- ambiguity—which model to use?

$$R(f) = \frac{S_{R}}{S_{Q}} \left(1 + a_{2}f^{2} + a_{4}f^{4} + a_{6}f^{6} + \dots \right)$$





- **contour plot of total uncertainty versus model complexity and bandwidth**
- **cross-validation method** (Kevin, Coakley et. al., arXiv:1606.05907)
- select the optimal polynomial model and bandwidth by minimizing the uncertainty that accounts for both random and systematic effects

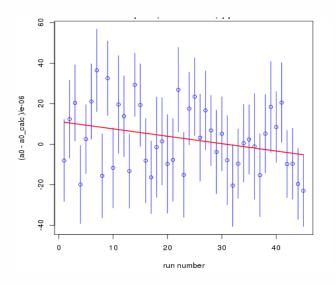


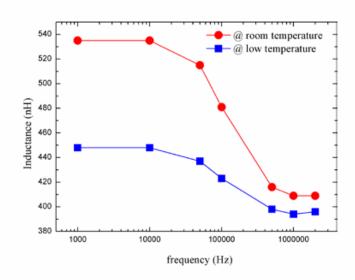
Uncertainty Budget

$$(k_{\rm B}-k_{\rm B}^{2010}) / k_{\rm B}^{2010} = +1.8 \times 10^{-6}$$

Component	$u_{\rm r}/10^{-6}$
Statistical	3.2
Correction Model ambiguity	1.8
Dielectric losses	1.0
EMI	0.4
Nonlinearity	0.1
R measurement	0.53
TPW	0.35
QVNS waveform	0.1
$u_{\rm r}(k_{\rm B})$	3.9







Problems to solve:

- **■** drifting trend, probably caused by instability of the stray impedance
- **■** the stray inductance dependent on both frequency and temperature
- **thin, low TCR, coax cable**



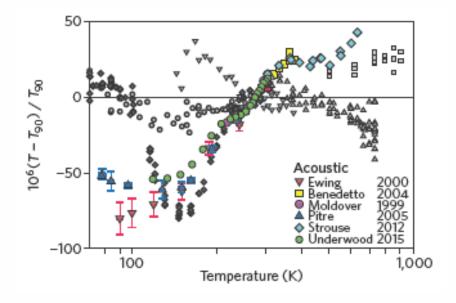
Problems to solve:

- **match** source impedance to the transmission line characteristic impedance
- **four channel system to halve the measurement time (NIST)**

Uncertainty limitation?

- **u** fundamental limitation?
- **practical limitation**
 - bandwidth
 - time (1000 h for 3 ppm, 1 year for 1 ppm!)





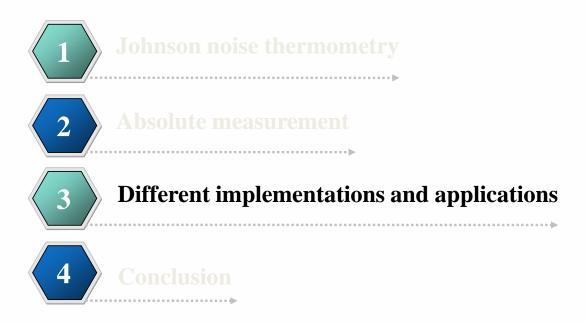
M. R. Moldover et. al., Nature Physics, 12 (2016) pp 7-11.

High temperatures

- different fixed-point temperatures of Zn, Ag, Cu and Pd (PTB)
- **■** uncertainty < 0.004% has been demonstrated up to 800 K (NIST)
- \blacksquare T-T₉₀, by NIST, NIM, NMIJ, PTB
- **could be competitive in 600-1000 K with AGT and radiation thermometry**

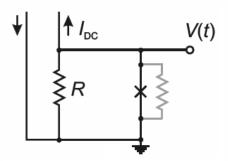


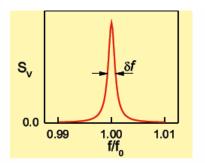
Outline





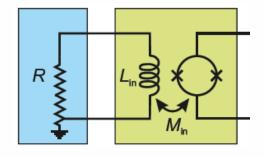
SQUID-based noise thermometer





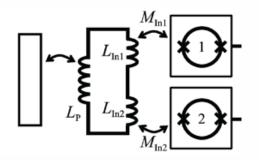
Kamper, Zimmermann, JAP 42 (1971), 132

■ R-SQUID noise thermometer



Shibahara *et al*, Phil. Trans. R. Soc. A 374 (2016) 20150054.

■ Current Sensor Noise Thermometer

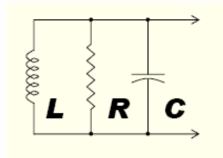


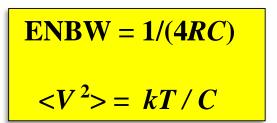
Kirste *et al*, Phil. Trans. R. Soc. A 374 (2016) 20150050.

- **Magnetic Field Fluctuation Thermometer**
- 1 mK 5 K, thermodynamic temperature

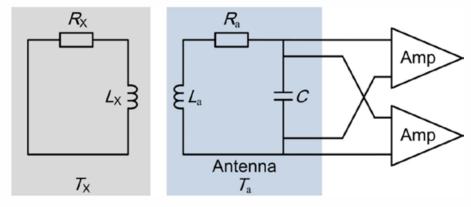


Tuned-RLC noise thermometer





Pepper, Brown, J Phys. E, 42 (1979), 31

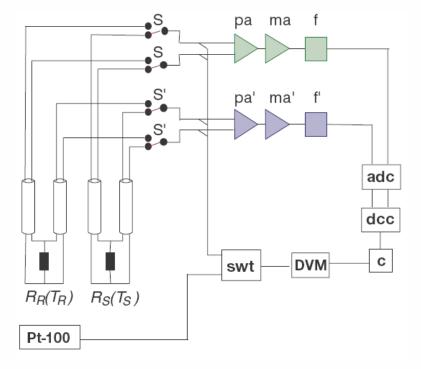


- **■** the noise amplitude is determined by a capacitor
- **resistance measurement is not necessary**
- **■** inductively coupling allows non-contact measurement
- **steel industry**



Dual noise-thermocouple thermometer





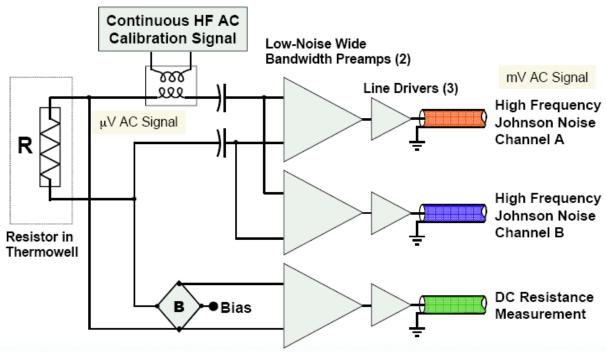
F Edler et al, Meas. Sci. Technol.26 (2015) 015102.

- **combine noise and thermocouple thermometry**
- proposed by Brixy for use in nuclear plant or space satellite power system
- **calibration** in situ

- recently demonstrated up to 1450 °C at PTB
- uncertainty of 0.1% under lab conditions, and double under industrial conditions



Dual noise-resistance thermometer

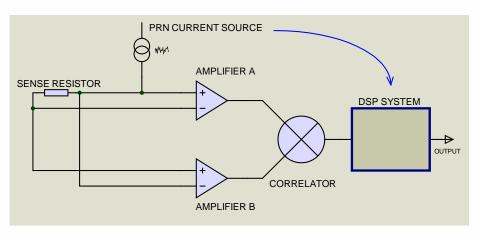


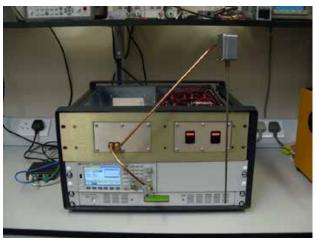
from David Holcomb, ORNL

- single sensor, fast resistance mode or slow noise thermometry mode
- **continuous** AC signal is used to calibrate



Practical noise thermometer





(from Paul Bramley of Metrosol)

- **■** inject precision current as calibration signal
- 5 kWsensor, 1MHz bandwidth
- standard deviation 0.14°C at 20 °C



- **remaining challenges: strong EMI, harsh environments**
- **rapid progress of electronics made it viable for industry**
- suited for high-temperature, high accuracy applications:
 - next generation of nuclear power plant (~850 °C)
 - emission controls (0.1 °C @ ~850 °C)
 - aerospace (satellite with significant solar exposure, ionizing radiation)
 - high value manufacture (turbine, technical ceramics)



Outline





- **purely electronic approach, appealing alternative to other primary thermometry**
- technology breakthroughs (switch correlator, ADC, QVNS) made it possible to contribute to the redefinition of kelvin
- \blacksquare could be competitive with AGT and radiation thermometry in range of 600 K 1000 K
- different implementations have been demonstrated under lab conditions, cover temperature from millikelvin to over 1500 °C
- high temperature, high accuracy applications in industry becoming more practical



- NIST: Samuel Benz, Kevin Coakley, Alessio Pollarolo, Horst Rogalla, Weston Tew
- **MSL: Rod White**
- **PTB: Frank Edler, Alexander Kirste,**
- **NPL: Jonathan Pearce**
- **Metrosol Limited: Paul Bramley**



Thanks for your attention!